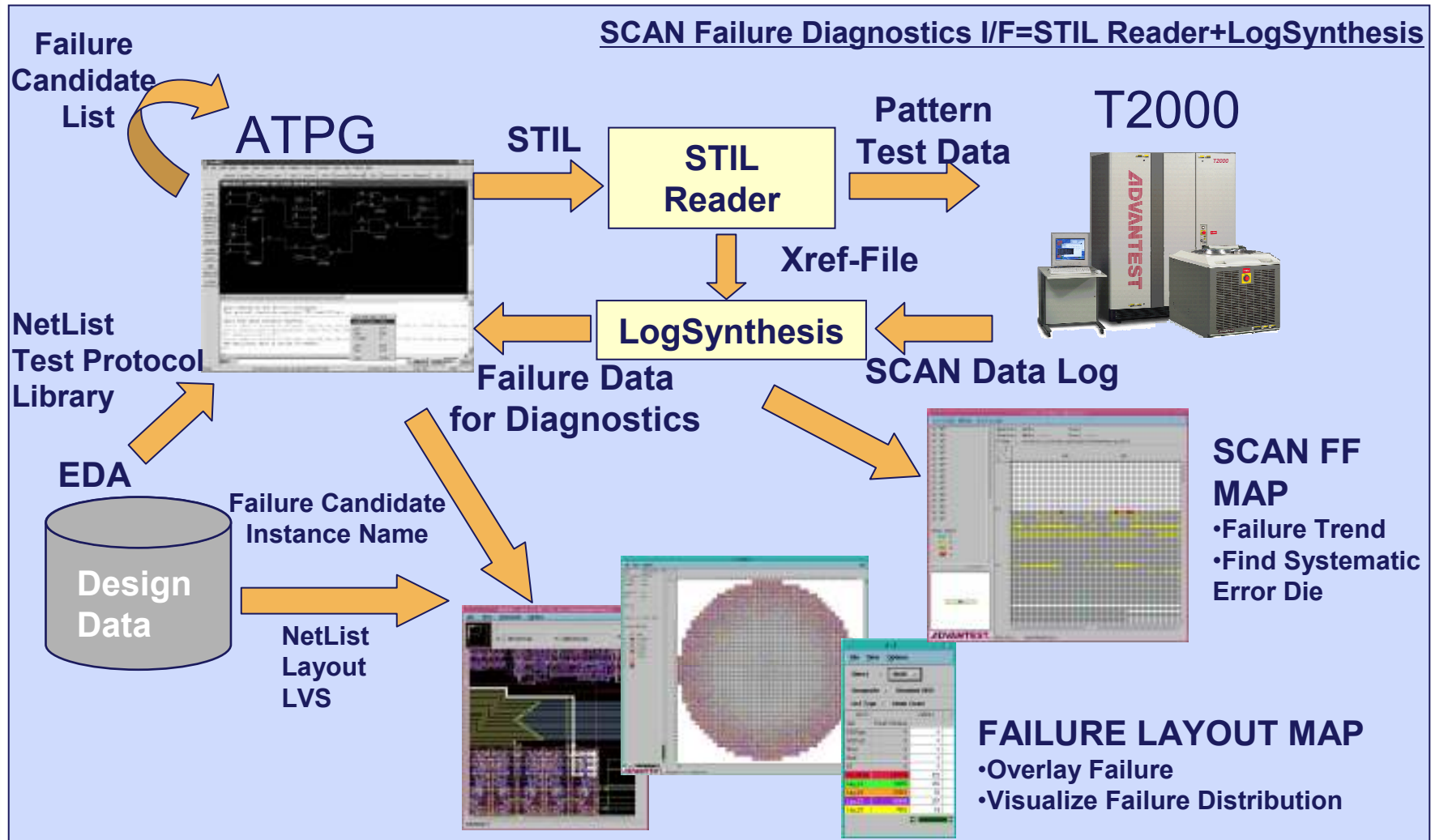


SCAN Failure Diagnostics I/F for T2000

Presented to STDF Working Group

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SCAN Failure Diagnostics I/F - System Overview



Product Goals:

Reduce Time to Market

Reduce Cost

- Reduce Design and Manufacturing Cost
- Reduce Test Cost - Implement a DFT Methodology

Improve Yield - Resolve Complex Failure by Failure Diagnostics

Problems:

EDA Failure Diagnostics (input) data format is different depending on customer and EDA vendor

Solution:

Standardization of Diagnostics data format for EDA Diagnostics tools

